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solder**

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Foreword

This translation has been made based on the original Japanese Industrial Standard revised by the Minister of Economy, Trade and Industry through deliberations at the Japanese Industrial Standards Committee as the result of proposal for revision of Japanese Industrial Standard submitted by The Japan Welding Engineering Society (JWES)/Japanese Standards Association (JSA) with the draft being attached, based on the provision of Article 12 Clause 1 of the Industrial Standardization Law applicable to the case of revision by the provision of Article 14.

Consequently **JIS Z 3910**:2008 is replaced with this Standard.

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Methods for chemical analysis of solder

1 Scope

This Japanese Industrial Standard specifies the methods for determination of alloy components (tin, silver, antimony, bismuth, copper, indium, zinc, nickel, germanium and lead) and of impurities (lead, silver, antimony, bismuth, copper, indium, zinc, nickel, iron, aluminium, arsenic, cadmium and gold) in the solder.

2 Normative references

The following standards contain provisions which, through reference in this text, constitute provisions of this Standard. The most recent editions of the standards (including amendments) indicated below shall be applied.

- JIS H 0301 *General rules for sampling, sample preparation and analytical testing of non-ferrous metals*
- JIS H 0321 *General rules for inspection of non-ferrous metal materials*
- JIS H 2105 *Pig lead*
- JIS K 0050 *General rules for chemical analysis*
- JIS K 0116 *General rules for atomic emission spectrometry*
- JIS K 0119 *General rules for X-ray fluorescence analysis*
- JIS K 0121 *General rules for atomic absorption spectrometry*
- JIS K 0211 *Technical terms for analytical chemistry (General part)*
- JIS K 1105 *Argon*
- JIS Z 2611 *General rules for radioelectric emission spectrochemical analysis of metal materials*
- JIS Z 3001-1 *Welding and allied processes—Vocabulary—Part 1: General*
- JIS Z 3001-3 *Welding and allied processes—Vocabulary—Part 3: Soldering and brazing*
- JIS Z 3282 *Soft solders—Chemical compositions and forms*
- JIS Z 8401 *Guide to the rounding of numbers*

3 Terms and definitions

For the purposes of this Standard, the terms and definitions given in **JIS K 0211**, **JIS Z 3001-1** and **JIS Z 3001-3** apply.

4 General

4.1 General matters of chemical analysis

General matters of chemical analysis given in **JIS K 0050**, **JIS K 0116**, **JIS K 0119**, **JIS K 0121**, **JIS Z 2611**, and the following apply.